

A Scanning Electron Microscope (SEM) is utilised in almost every material challenge, whether its development work, troubleshooting or documentation of microstructure and chemistry. Our SEM is an important tool in research and development and its possibilities are almost endless within materials characterisation.

TECHNICAL ASPECTS

- “FEG-SEM”- Field Emission Gun-Scanning Electron Microscope
- Model: Zeiss Merlin Compact with;
- Secondary, backscatter and in-lens duo detectors
- Quantax EDS-system from Bruker (Xflash 6/30)

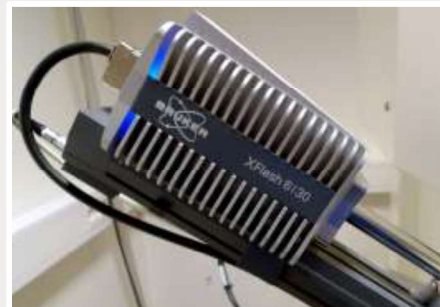
TYPICAL APPLICATIONS

- Identification of phases and particles
- Element mapping and line scan with chemical composition
- Size and classification of particles and phases
- Microstructure investigations
- Identification of material defects
- High magnification and high resolution imaging
- Asbestos surveys



RELATED EQUIPMENT

- **QUORUM 150T ES.** Our Coater is often used when dealing with non-conducting materials. We can apply a thin layer of Au, Pt, Cr or C depending on the examination type
- **AMICS software** (Advanced Mineral Identification and Characterization System). AMICS is a powerful tool which allow us to quantify large areas on a micron level



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